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## **Computer Vision Techniques: Theory and Applications**

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Deadline for manuscript submissions:

closed (31 May 2022)

# **Message from the Guest Editors**

This Special Issue aims to provide a platform to publish recent original research, review papers or surveys in the state of the art of theoretical approaches and applications of computer vision.

Topics of interest to this Special Issue include but are not limited to:

- Image processing in CV;
- Feature detection and matching;
- Image segmentation;
- Image registration;
- Object recognition and tracking;
- Image classification and recognition;
- Motion analysis;
- Machine learning for CV;
- Biologically inspired CV;
- Applications.

Welcome to contribute.











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## **Editor-in-Chief**

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## **Message from the Editor-in-Chief**

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